

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination JEON ET AL.	
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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-5,279,623	01-1994	Watanabe et al.	29/25.03
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L	US-			
M	US-			

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**NON-PATENT DOCUMENTS**

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